



Welcome to [E-XFL.COM](https://www.e-xfl.com)

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	216
Number of Logic Elements/Cells	972
Total RAM Bits	24576
Number of I/O	92
Number of Gates	30000
Voltage - Supply	2.375V ~ 2.625V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	144-TFBGA, CSPBGA
Supplier Device Package	144-LCSBGA (12x12)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc2s30-6cs144c

Spartan-II Product Availability

Table 2 shows the maximum user I/Os available on the device and the number of user I/Os available for each device/package combination. The four global clock pins are usable as additional user I/Os when not used as a global clock pin. These pins are not included in user I/O counts.

Table 2: Spartan-II FPGA User I/O Chart⁽¹⁾

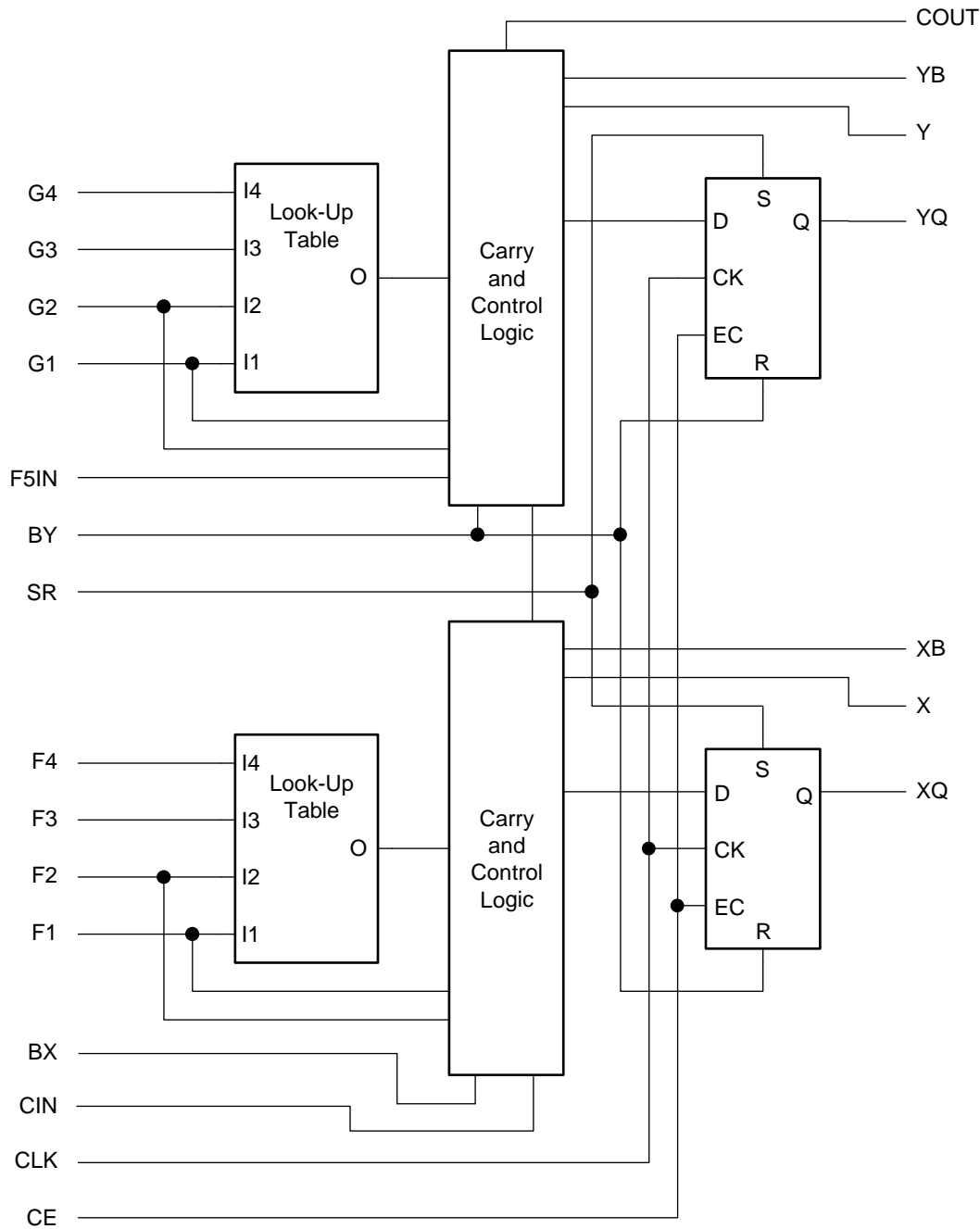
Device	Maximum User I/O	Available User I/O According to Package Type					
		VQ100 VQG100	TQ144 TQG144	CS144 CSG144	PQ208 PQG208	FG256 FGG256	FG456 FGG456
XC2S15	86	60	86	(Note 2)	-	-	-
XC2S30	92	60	92	92	(Note 2)	-	-
XC2S50	176	-	92	-	140	176	-
XC2S100	176	-	92	-	140	176	(Note 2)
XC2S150	260	-	-	-	140	176	260
XC2S200	284	-	-	-	140	176	284

Notes:

1. All user I/O counts do not include the four global clock/user input pins.
2. Discontinued by [PDN2004-01](#).

Revision History

Date	Version No.	Description
09/18/00	2.0	Sectioned the Spartan-II Family data sheet into four modules. Added industrial temperature range information.
10/31/00	2.1	Removed Power down feature.
03/05/01	2.2	Added statement on PROMs.
11/01/01	2.3	Updated Product Availability chart. Minor text edits.
09/03/03	2.4	Added device part marking.
08/02/04	2.5	Added information on Pb-free packaging options and removed discontinued options.
06/13/08	2.8	Updated description and links. Updated all modules for continuous page, figure, and table numbering. Synchronized all modules to v2.8.



DS001_04_091400

Figure 4: **Spartan-II CLB Slice** (two identical slices in each CLB)

Storage Elements

Storage elements in the Spartan-II FPGA slice can be configured either as edge-triggered D-type flip-flops or as level-sensitive latches. The D inputs can be driven either by function generators within the slice or directly from slice inputs, bypassing the function generators.

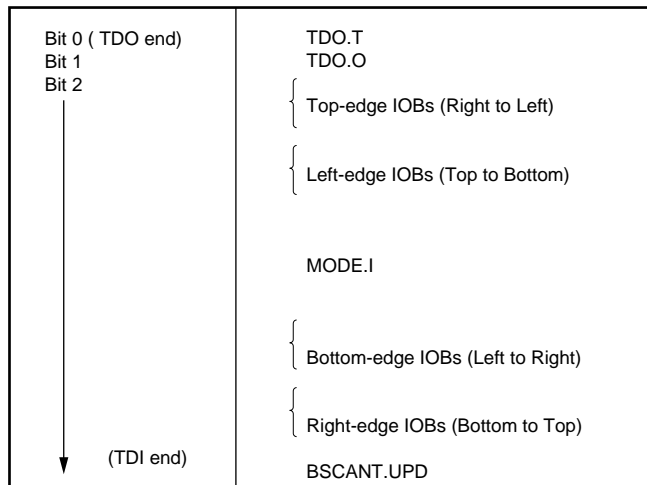
In addition to Clock and Clock Enable signals, each slice has synchronous set and reset signals (SR and BY). SR forces a storage element into the initialization state specified for it in the configuration. BY forces it into the

opposite state. Alternatively, these signals may be configured to operate asynchronously.

All control signals are independently invertible, and are shared by the two flip-flops within the slice.

Additional Logic

The F5 multiplexer in each slice combines the function generator outputs. This combination provides either a function generator that can implement any 5-input function, a 4:1 multiplexer, or selected functions of up to nine inputs.



DS001_10_032300

Figure 10: Boundary Scan Bit Sequence

Development System

Spartan-II FPGAs are supported by the Xilinx ISE® development tools. The basic methodology for Spartan-II FPGA design consists of three interrelated steps: design entry, implementation, and verification. Industry-standard tools are used for design entry and simulation, while Xilinx provides proprietary architecture-specific tools for implementation.

The Xilinx development system is integrated under a single graphical interface, providing designers with a common user interface regardless of their choice of entry and verification tools. The software simplifies the selection of implementation options with pull-down menus and on-line help.

For HDL design entry, the Xilinx FPGA development system provides interfaces to several synthesis design environments.

A standard interface-file specification, Electronic Design Interchange Format (EDIF), simplifies file transfers into and out of the development system.

Spartan-II FPGAs supported by a unified library of standard functions. This library contains over 400 primitives and macros, ranging from 2-input AND gates to 16-bit accumulators, and includes arithmetic functions, comparators, counters, data registers, decoders, encoders, I/O functions, latches, Boolean functions, multiplexers, shift registers, and barrel shifters.

The design environment supports hierarchical design entry. These hierarchical design elements are automatically combined by the implementation tools. Different design entry tools can be combined within a hierarchical design, thus allowing the most convenient entry method to be used for each portion of the design.

Design Implementation

The place-and-route tools (PAR) automatically provide the implementation flow described in this section. The partitioner takes the EDIF netlist for the design and maps the logic into the architectural resources of the FPGA (CLBs and IOBs, for example). The placer then determines the best locations for these blocks based on their interconnections and the desired performance. Finally, the router interconnects the blocks.

The PAR algorithms support fully automatic implementation of most designs. For demanding applications, however, the user can exercise various degrees of control over the process. User partitioning, placement, and routing information is optionally specified during the design-entry process. The implementation of highly structured designs can benefit greatly from basic floorplanning.

The implementation software incorporates timing-driven placement and routing. Designers specify timing requirements along entire paths during design entry. The timing path analysis routines in PAR then recognize these user-specified requirements and accommodate them.

Timing requirements are entered in a form directly relating to the system requirements, such as the targeted clock frequency, or the maximum allowable delay between two registers. In this way, the overall performance of the system along entire signal paths is automatically tailored to user-generated specifications. Specific timing information for individual nets is unnecessary.

Design Verification

In addition to conventional software simulation, FPGA users can use in-circuit debugging techniques. Because Xilinx devices are infinitely reprogrammable, designs can be verified in real time without the need for extensive sets of software simulation vectors.

The development system supports both software simulation and in-circuit debugging techniques. For simulation, the system extracts the post-layout timing information from the design database, and back-annotates this information into the netlist for use by the simulator. Alternatively, the user can verify timing-critical portions of the design using the static timing analyzer.

For in-circuit debugging, the development system includes a download cable, which connects the FPGA in the target system to a PC or workstation. After downloading the design into the FPGA, the designer can read back the contents of the flip-flops, and so observe the internal logic state. Simple modifications can be downloaded into the system in a matter of minutes.

Table 11: Available Library Primitives

Primitive	Port A Width	Port B Width
RAMB4_S4	4	N/A
RAMB4_S4_S4		4
RAMB4_S4_S8		8
RAMB4_S4_S16		16
RAMB4_S8	8	N/A
RAMB4_S8_S8		8
RAMB4_S8_S16		16
RAMB4_S16	16	N/A
RAMB4_S16_S16		16

Port Signals

Each block RAM port operates independently of the others while accessing the same set of 4096 memory cells.

Table 12 describes the depth and width aspect ratios for the block RAM memory.

Table 12: Block RAM Port Aspect Ratios

Width	Depth	ADDR Bus	Data Bus
1	4096	ADDR<11:0>	DATA<0>
2	2048	ADDR<10:0>	DATA<1:0>
4	1024	ADDR<9:0>	DATA<3:0>
8	512	ADDR<8:0>	DATA<7:0>
16	256	ADDR<7:0>	DATA<15:0>

Clock—CLK[A/B]

Each port is fully synchronous with independent clock pins. All port input pins have setup time referenced to the port CLK pin. The data output bus has a clock-to-out time referenced to the CLK pin.

Enable—EN[A/B]

The enable pin affects the read, write and reset functionality of the port. Ports with an inactive enable pin keep the output pins in the previous state and do not write data to the memory cells.

Write Enable—WE[A/B]

Activating the write enable pin allows the port to write to the memory cells. When active, the contents of the data input bus are written to the RAM at the address pointed to by the address bus, and the new data also reflects on the data out bus. When inactive, a read operation occurs and the contents of the memory cells referenced by the address bus reflect on the data out bus.

Reset—RST[A/B]

The reset pin forces the data output bus latches to zero synchronously. This does not affect the memory cells of the RAM and does not disturb a write operation on the other port.

Address Bus—ADDR[A/B]<#:0>

The address bus selects the memory cells for read or write. The width of the port determines the required width of this bus as shown in Table 12.

Data In Bus—DI[A/B]<#:0>

The data in bus provides the new data value to be written into the RAM. This bus and the port have the same width, as shown in Table 12.

Data Output Bus—DO[A/B]<#:0>

The data out bus reflects the contents of the memory cells referenced by the address bus at the last active clock edge. During a write operation, the data out bus reflects the data in bus. The width of this bus equals the width of the port. The allowed widths appear in Table 12.

Inverting Control Pins

The four control pins (CLK, EN, WE and RST) for each port have independent inversion control as a configuration option.

Address Mapping

Each port accesses the same set of 4096 memory cells using an addressing scheme dependent on the width of the port. The physical RAM location addressed for a particular width are described in the following formula (of interest only when the two ports use different aspect ratios).

$$\text{Start} = ([\text{ADDR}_{\text{port}} + 1] * \text{Width}_{\text{port}}) - 1$$

$$\text{End} = \text{ADDR}_{\text{port}} * \text{Width}_{\text{port}}$$

Table 13 shows low order address mapping for each port width.

Table 13: Port Address Mapping

Port Width	Port Addresses																
1	4095...	15	14	13	12	11	10	9	8	7	6	5	4	3	2	1	0
2	2047...	07		06		05		04		03		02		01		00	
4	1023...	03				02				01				00			
8	511...	01								00							
16	255...	00															

Creating Larger RAM Structures

The block RAM columns have specialized routing to allow cascading blocks together with minimal routing delays. This achieves wider or deeper RAM structures with a smaller timing penalty than when using normal routing channels.

Location Constraints

Block RAM instances can have LOC properties attached to them to constrain the placement. The block RAM placement locations are separate from the CLB location naming convention, allowing the LOC properties to transfer easily from array to array.

The LOC properties use the following form:

LOC = RAMB4_R#C#

RAMB4_R0C0 is the upper left RAMB4 location on the device.

Conflict Resolution

The block RAM memory is a true dual-read/write port RAM that allows simultaneous access of the same memory cell from both ports. When one port writes to a given memory cell, the other port must not address that memory cell (for a write or a read) within the clock-to-clock setup window. The following lists specifics of port and memory cell write conflict resolution.

- If both ports write to the same memory cell simultaneously, violating the clock-to-clock setup requirement, consider the data stored as invalid.
- If one port attempts a read of the same memory cell the other simultaneously writes, violating the clock-to-clock setup requirement, the following occurs.
 - The write succeeds
 - The data out on the writing port accurately reflects the data written.
 - The data out on the reading port is invalid.

Conflicts do not cause any physical damage.

Single Port Timing

Figure 33 shows a timing diagram for a single port of a block RAM memory. The block RAM AC switching characteristics are specified in the data sheet. The block RAM memory is initially disabled.

At the first rising edge of the CLK pin, the ADDR, DI, EN, WE, and RST pins are sampled. The EN pin is High and the WE pin is Low indicating a read operation. The DO bus contains the contents of the memory location, 0x00, as indicated by the ADDR bus.

At the second rising edge of the CLK pin, the ADDR, DI, EN, WR, and RST pins are sampled again. The EN and WE pins are High indicating a write operation. The DO bus mirrors

the DI bus. The DI bus is written to the memory location 0x0F.

At the third rising edge of the CLK pin, the ADDR, DI, EN, WR, and RST pins are sampled again. The EN pin is High and the WE pin is Low indicating a read operation. The DO bus contains the contents of the memory location 0x7E as indicated by the ADDR bus.

At the fourth rising edge of the CLK pin, the ADDR, DI, EN, WR, and RST pins are sampled again. The EN pin is Low indicating that the block RAM memory is now disabled. The DO bus retains the last value.

Dual Port Timing

Figure 34 shows a timing diagram for a true dual-port read/write block RAM memory. The clock on port A has a longer period than the clock on Port B. The timing parameter T_{BCCS} , (clock-to-clock setup) is shown on this diagram. The parameter, T_{BCCS} is violated once in the diagram. All other timing parameters are identical to the single port version shown in Figure 33.

T_{BCCS} is only of importance when the address of both ports are the same and at least one port is performing a write operation. When the clock-to-clock set-up parameter is violated for a WRITE-WRITE condition, the contents of the memory at that location will be invalid. When the clock-to-clock set-up parameter is violated for a WRITE-READ condition, the contents of the memory will be correct, but the read port will have invalid data. At the first rising edge of the CLKA, memory location 0x00 is to be written with the value 0xAAAA and is mirrored on the DOA bus. The last operation of Port B was a read to the same memory location 0x00. The DOB bus of Port B does not change with the new value on Port A, and retains the last read value. A short time later, Port B executes another read to memory location 0x00, and the DOB bus now reflects the new memory value written by Port A.

At the second rising edge of CLKA, memory location 0x7E is written with the value 0x9999 and is mirrored on the DOA bus. Port B then executes a read operation to the same memory location without violating the T_{BCCS} parameter and the DOB reflects the new memory values written by Port A.

LVTTL output buffers have selectable drive strengths.

The format for LVTTL OBUF primitive names is as follows.

OBUF_<slew_rate>_<drive_strength>

<slew_rate> is either F (Fast), or S (Slow) and <drive_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24). The default is slew rate limited with 12 mA drive.

OBUF placement restrictions require that within a given V_{CCO} bank each OBUF share the same output source drive voltage. Input buffers of any type and output buffers that do not require V_{CCO} can be placed within any V_{CCO} bank.

Table 17 summarizes the output compatibility requirements. The LOC property can specify a location for the OBUF.

Table 17: Output Standards Compatibility Requirements

Rule 1	Only outputs with standards which share compatible V_{CCO} may be used within the same bank.
Rule 2	There are no placement restrictions for outputs with standards that do not require a V_{CCO} .
V_{CCO}	Compatible Standards
3.3	LVTTL, SSTL3_I, SSTL3_II, CTT, AGP, GTL, GTL+, PCI33_3, PCI66_3
2.5	SSTL2_I, SSTL2_II, LVCMOS2, GTL, GTL+
1.5	HSTL_I, HSTL_III, HSTL_IV, GTL, GTL+

OBUFT

The generic 3-state output buffer OBUFT, shown in Figure 39, typically implements 3-state outputs or bidirectional I/O.

With no extension or property specified for the generic OBUFT primitive, the assumed standard is slew rate limited LVTTL with 12 mA drive strength.

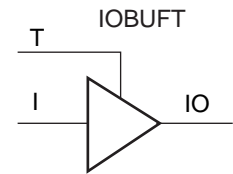
The LVTTL OBUFT can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL 3-state output buffers have selectable drive strengths.

The format for LVTTL OBUFT primitive names is as follows.

OBUFT_<slew_rate>_<drive_strength>

<slew_rate> can be either F (Fast), or S (Slow) and <drive_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24).



DS001_39_032300

Figure 39: 3-State Output Buffer Primitive (OBUFT)

The Versatile I/O OBUFT placement restrictions require that within a given V_{CCO} bank each OBUFT share the same output source drive voltage. Input buffers of any type and output buffers that do not require V_{CCO} can be placed within the same V_{CCO} bank.

The LOC property can specify a location for the OBUFT.

3-state output buffers and bidirectional buffers can have either a weak pull-up resistor, a weak pull-down resistor, or a weak "keeper" circuit. Control this feature by adding the appropriate primitive to the output net of the OBUFT (PULLUP, PULLDOWN, or KEEPER).

The weak "keeper" circuit requires the input buffer within the IOB to sample the I/O signal. So, OBUFTs programmed for an I/O standard that requires a V_{REF} have automatic placement of a V_{REF} in the bank with an OBUFT configured with a weak "keeper" circuit. This restriction does not affect most circuit design as applications using an OBUFT configured with a weak "keeper" typically implement a bidirectional I/O. In this case the IBUF (and the corresponding V_{REF}) are explicitly placed.

The LOC property can specify a location for the OBUFT.

IOBUF

Use the IOBUF primitive for bidirectional signals that require both an input buffer and a 3-state output buffer with an active high 3-state pin. The generic input/output buffer IOBUF appears in Figure 40.

With no extension or property specified for the generic IOBUF primitive, the assumed standard is LVTTL input buffer and slew rate limited LVTTL with 12 mA drive strength for the output buffer.

The LVTTL IOBUF can support one of two slew rate modes to minimize bus transients. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals.

LVTTL bidirectional buffers have selectable output drive strengths.

The format for LVTTL IOBUF primitive names is as follows:

IOBUF_<slew_rate>_<drive_strength>

<slew_rate> can be either F (Fast), or S (Slow) and <drive_strength> is specified in milliamps (2, 4, 6, 8, 12, 16, or 24).

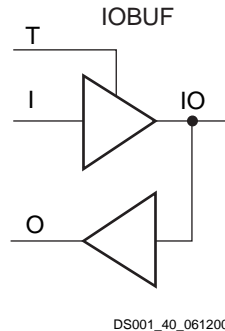


Figure 40: Input/Output Buffer Primitive (IOBUF)

When the IOBUF primitive supports an I/O standard such as LVTTL, LVCMOS, or PCI33_5, the IBUF automatically configures as a 5V tolerant input buffer unless the V_{CCO} for the bank is less than 2V. If the single-ended IBUF is placed in a bank with an HSTL standard ($V_{CCO} < 2V$), the input buffer is not 5V tolerant.

The voltage reference signal is "banked" within the Spartan-II device on a half-edge basis such that for all packages there are eight independent V_{REF} banks internally. See Figure 36, page 39 for a representation of the Spartan-II FPGA I/O banks. Within each bank approximately one of every six I/O pins is automatically configured as a V_{REF} input.

Additional restrictions on the Versatile I/O IOBUF placement require that within a given V_{CCO} bank each IOBUF must share the same output source drive voltage. Input buffers of any type and output buffers that do not require V_{CCO} can be placed within the same V_{CCO} bank. The LOC property can specify a location for the IOBUF.

An optional delay element is associated with the input path in each IOBUF. When the IOBUF drives an input flip-flop within the IOB, the delay element activates by default to ensure a zero hold-time requirement. Override this default with the NODELAY=TRUE property.

In the case when the IOBUF does not drive an input flip-flop within the IOB, the delay element de-activates by default to provide higher performance. To delay the input signal, activate the delay element with the DELAY=TRUE property.

3-state output buffers and bidirectional buffers can have either a weak pull-up resistor, a weak pull-down resistor, or a weak "keeper" circuit. Control this feature by adding the appropriate primitive to the output net of the IOBUF (PULLUP, PULLDOWN, or KEEPER).

Versatile I/O Properties

Access to some of the Versatile I/O features (for example, location constraints, input delay, output drive strength, and slew rate) is available through properties associated with these features.

Input Delay Properties

An optional delay element is associated with each IBUF. When the IBUF drives a flip-flop within the IOB, the delay element activates by default to ensure a zero hold-time requirement. Use the NODELAY=TRUE property to override this default.

In the case when the IBUF does not drive a flip-flop within the IOB, the delay element by default de-activates to provide higher performance. To delay the input signal, activate the delay element with the DELAY=TRUE property.

IOB Flip-Flop/Latch Property

The I/O Block (IOB) includes an optional register on the input path, an optional register on the output path, and an optional register on the 3-state control pin. The design implementation software automatically takes advantage of these registers when the following option for the Map program is specified:

```
map -pr b <filename>
```

Alternatively, the IOB = TRUE property can be placed on a register to force the mapper to place the register in an IOB.

Location Constraints

Specify the location of each Versatile I/O primitive with the location constraint LOC attached to the Versatile I/O primitive. The external port identifier indicates the value of the location constrain. The format of the port identifier depends on the package chosen for the specific design.

The LOC properties use the following form:

```
LOC=A42
```

```
LOC=P37
```

Output Slew Rate Property

In the case of the LVTTL output buffers (OBUF, OBUFT, and IOBUF), slew rate control can be programmed with the SLEW= property. By default, the slew rate for each output buffer is reduced to minimize power bus transients when switching non-critical signals. The SLEW= property has one of the two following values.

```
SLEW=SLOW
```

```
SLEW=FAST
```

Output Drive Strength Property

For the LVTTL output buffers (OBUF, OBUFT, and IOBUF, the desired drive strength can be specified with the DRIVE=

Revision History

Date	Version	Description
09/18/00	2.0	Sectioned the Spartan-II Family data sheet into four modules. Corrected banking description.
03/05/01	2.1	Clarified guidelines for applying power to V_{CCINT} and V_{CCO}
09/03/03	2.2	<p>The following changes were made:</p> <ul style="list-style-type: none">• "Serial Modes," page 20 cautions about toggling \overline{WRITE} during serial configuration.• Maximum V_{IH} values in Table 32 and Table 33 changed to 5.5V.• In "Boundary Scan," page 13, removed sentence about lack of INTEST support.• In Table 9, page 17, added note about the state of I/Os after power-on.• In "Slave Parallel Mode," page 23, explained configuration bit alignment to SelectMap port.
06/13/08	2.8	Added note that TDI, TMS, and TCK have a default pull-up resistor. Added note on maximum daisy chain limit. Updated Figure 15 and Figure 18 since Mode pins can be pulled up to either 2.5V or 3.3V. Updated DLL section. Recommended using property or attribute instead of primitive to define I/O properties. Updated description and links. Updated all modules for continuous page, figure, and table numbering. Synchronized all modules to v2.8.

IOB Output Delay Adjustments for Different Standards⁽¹⁾

Output delays terminating at a pad are specified for LVTTTL with 12 mA drive and fast slew rate. For other standards, adjust the delays by the values shown. A delay adjusted in this way constitutes a worst-case limit.

Symbol	Description	Standard	Speed Grade		Units
			-6	-5	
Output Delay Adjustments (Adj)					
T _{OLVTTL_S2}	Standard-specific adjustments for output delays terminating at pads (based on standard capacitive load, C _{SL})	LVTTTL, Slow, 2 mA	14.2	16.9	ns
T _{OLVTTL_S4}		4 mA	7.2	8.6	ns
T _{OLVTTL_S6}		6 mA	4.7	5.5	ns
T _{OLVTTL_S8}		8 mA	2.9	3.5	ns
T _{OLVTTL_S12}		12 mA	1.9	2.2	ns
T _{OLVTTL_S16}		16 mA	1.7	2.0	ns
T _{OLVTTL_S24}		24 mA	1.3	1.5	ns
T _{OLVTTL_F2}		LVTTTL, Fast, 2 mA	12.6	15.0	ns
T _{OLVTTL_F4}		4 mA	5.1	6.1	ns
T _{OLVTTL_F6}		6 mA	3.0	3.6	ns
T _{OLVTTL_F8}		8 mA	1.0	1.2	ns
T _{OLVTTL_F12}		12 mA	0	0	ns
T _{OLVTTL_F16}		16 mA	−0.1	−0.1	ns
T _{OLVTTL_F24}		24 mA	−0.1	−0.2	ns
T _{OLVCMOS2}		LVC MOS2	0.2	0.2	ns
T _{OPCI33_3}		PCI, 33 MHz, 3.3V	2.4	2.9	ns
T _{OPCI33_5}		PCI, 33 MHz, 5.0V	2.9	3.5	ns
T _{OPCI66_3}		PCI, 66 MHz, 3.3V	−0.3	−0.4	ns
T _{OGTL}		GTL	0.6	0.7	ns
T _{OGTLP}		GTL+	0.9	1.1	ns
T _{OHSTL_I}		HSTL I	−0.4	−0.5	ns
T _{OHSTL_III}		HSTL III	−0.8	−1.0	ns
T _{OHSTL_IV}		HSTL IV	−0.9	−1.1	ns
T _{OSSTL2_I}		SSTL2 I	−0.4	−0.5	ns
T _{OSSTL2_II}	SSTL2 II	−0.8	−1.0	ns	
T _{OSSTL3_I}	SSTL3 I	−0.4	−0.5	ns	
T _{OSSTL3_II}	SSTL3 II	−0.9	−1.1	ns	
T _{OCTT}	CTT	−0.5	−0.6	ns	
T _{OAGP}	AGP	−0.8	−1.0	ns	

Notes:

- Output timing is measured at 1.4V with 35 pF external capacitive load for LVTTTL. For other I/O standards and different loads, see the tables "Constants for Calculating TIOOP" and "Delay Measurement Methodology," page 60.

DLL Timing Parameters

All devices are 100 percent functionally tested. Because of the difficulty in directly measuring many internal timing parameters, those parameters are derived from benchmark

timing patterns. The following guidelines reflect worst-case values across the recommended operating conditions.

Symbol	Description	Speed Grade				Units
		-6		-5		
		Min	Max	Min	Max	
F _{CLKINHF}	Input clock frequency (CLKDLLHF)	60	200	60	180	MHz
F _{CLKINLF}	Input clock frequency (CLKDLL)	25	100	25	90	MHz
T _{DLLPWHF}	Input clock pulse width (CLKDLLHF)	2.0	-	2.4	-	ns
T _{DLLPWL}	Input clock pulse width (CLKDLL)	2.5	-	3.0	-	ns

DLL Clock Tolerance, Jitter, and Phase Information

All DLL output jitter and phase specifications were determined through statistical measurement at the package pins using a clock mirror configuration and matched drivers.

Figure 52, page 63, provides definitions for various parameters in the table below.

Symbol	Description	F _{CLKIN}	CLKDLLHF		CLKDLL		Units
			Min	Max	Min	Max	
T _{IPTOL}	Input clock period tolerance		-	1.0	-	1.0	ns
T _{IJTCC}	Input clock jitter tolerance (cycle-to-cycle)		-	±150	-	±300	ps
T _{LOCK}	Time required for DLL to acquire lock	> 60 MHz	-	20	-	20	μs
		50-60 MHz	-	-	-	25	μs
		40-50 MHz	-	-	-	50	μs
		30-40 MHz	-	-	-	90	μs
		25-30 MHz	-	-	-	120	μs
T _{OJITCC}	Output jitter (cycle-to-cycle) for any DLL clock output ⁽¹⁾		-	±60	-	±60	ps
T _{PHIO}	Phase offset between CLKIN and CLKO ⁽²⁾		-	±100	-	±100	ps
T _{PHOO}	Phase offset between clock outputs on the DLL ⁽³⁾		-	±140	-	±140	ps
T _{PHIOM}	Maximum phase difference between CLKIN and CLKO ⁽⁴⁾		-	±160	-	±160	ps
T _{PHOOM}	Maximum phase difference between clock outputs on the DLL ⁽⁵⁾		-	±200	-	±200	ps

Notes:

- Output Jitter** is cycle-to-cycle jitter measured on the DLL output clock, *excluding* input clock jitter.
- Phase Offset between CLKIN and CLKO** is the worst-case fixed time difference between rising edges of CLKIN and CLKO, *excluding* output jitter and input clock jitter.
- Phase Offset between Clock Outputs on the DLL** is the worst-case fixed time difference between rising edges of any two DLL outputs, *excluding* Output Jitter and input clock jitter.
- Maximum Phase Difference between CLKIN and CLKO** is the sum of Output Jitter and Phase Offset between CLKIN and CLKO, or the greatest difference between CLKIN and CLKO rising edges due to DLL alone (*excluding* input clock jitter).
- Maximum Phase Difference between Clock Outputs on the DLL** is the sum of Output Jitter and Phase Offset between any two DLL clock outputs, or the greatest difference between any two DLL output rising edges due to DLL alone (*excluding* input clock jitter).

XC2S50 Device Pinouts (Continued)

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
I/O	5	P99	P63	P6	326
GND	-	P98	P64	GND*	-
V _{CCO}	5	-	P65	V _{CCO} Bank 5*	-
V _{CCINT}	-	P97	P66	V _{CCINT} *	-
I/O	5	P96	P67	R6	329
I/O	5	P95	P68	M7	332
I/O	5	-	P69	N7	338
I/O	5	-	P70	T6	341
I/O	5	-	P71	P7	344
GND	-	-	P72	GND*	-
I/O, V _{REF}	5	P94	P73	P8	347
I/O	5	-	P74	R7	350
I/O	5	-	-	T7	353
I/O	5	P93	P75	T8	356
V _{CCINT}	-	P92	P76	V _{CCINT} *	-
I, GCK1	5	P91	P77	R8	365
V _{CCO}	5	P90	P78	V _{CCO} Bank 5*	-
V _{CCO}	4	P90	P78	V _{CCO} Bank 4*	-
GND	-	P89	P79	GND*	-
I, GCK0	4	P88	P80	N8	366
I/O	4	P87	P81	N9	370
I/O	4	P86	P82	R9	373
I/O	4	-	-	N10	376
I/O	4	-	P83	T9	379
I/O, V _{REF}	4	P85	P84	P9	382
GND	-	-	P85	GND*	-
I/O	4	-	P86	M10	385
I/O	4	-	P87	R10	388
I/O	4	-	P88	P10	391
I/O	4	P84	P89	T10	397
I/O	4	P83	P90	R11	400
V _{CCINT}	-	P82	P91	V _{CCINT} *	-
V _{CCO}	4	-	P92	V _{CCO} Bank 4*	-
GND	-	P81	P93	GND*	-
I/O	4	P80	P94	M11	403
I/O	4	P79	P95	T11	406
I/O	4	P78	P96	N11	409
I/O	4	-	-	R12	412

XC2S50 Device Pinouts (Continued)

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
I/O	4	-	P97	P11	415
I/O, V _{REF}	4	P77	P98	T12	418
GND	-	-	-	GND*	-
I/O	4	-	P99	T13	421
I/O	4	-	-	N12	424
I/O	4	P76	P100	R13	427
I/O	4	-	-	P12	430
I/O	4	P75	P101	P13	433
I/O	4	P74	P102	T14	436
GND	-	P73	P103	GND*	-
DONE	3	P72	P104	R14	439
V _{CCO}	4	P71	P105	V _{CCO} Bank 4*	-
V _{CCO}	3	P70	P105	V _{CCO} Bank 3*	-
PROGRAM	-	P69	P106	P15	442
I/O (INIT)	3	P68	P107	N15	443
I/O (D7)	3	P67	P108	N14	446
I/O	3	-	-	T15	449
I/O	3	P66	P109	M13	452
I/O	3	-	-	R16	455
I/O	3	-	P110	M14	458
GND	-	-	-	GND*	-
I/O, V _{REF}	3	P65	P111	L14	461
I/O	3	-	P112	M15	464
I/O	3	-	-	L12	467
I/O	3	P64	P113	P16	470
I/O	3	P63	P114	L13	473
I/O (D6)	3	P62	P115	N16	476
GND	-	P61	P116	GND*	-
V _{CCO}	3	-	P117	V _{CCO} Bank 3*	-
V _{CCINT}	-	-	P118	V _{CCINT} *	-
I/O (D5)	3	P60	P119	M16	479
I/O	3	P59	P120	K14	482
I/O	3	-	-	L16	485
I/O	3	-	P121	K13	488
I/O	3	-	P122	L15	491
I/O	3	-	P123	K12	494
GND	-	-	P124	GND*	-
I/O, V _{REF}	3	P58	P125	K16	497
I/O (D4)	3	P57	P126	J16	500

XC2S50 Device Pinouts (Continued)

XC2S50 Pad Name		TQ144	PQ208	FG256	Bndry Scan
Function	Bank				
I/O	0	-	-	D8	83
I/O	0	-	P188	A6	86
I/O, V _{REF}	0	P12	P189	B7	89
GND	-	-	P190	GND*	-
I/O	0	-	P191	C8	92
I/O	0	-	P192	D7	95
I/O	0	-	P193	E7	98
I/O	0	P11	P194	C7	104
I/O	0	P10	P195	B6	107
V _{CCINT}	-	P9	P196	V _{CCINT} *	-
V _{CCO}	0	-	P197	V _{CCO} Bank 0*	-
GND	-	P8	P198	GND*	-
I/O	0	P7	P199	A5	110
I/O	0	P6	P200	C6	113
I/O	0	-	P201	B5	116
I/O	0	-	-	D6	119
I/O	0	-	P202	A4	122
I/O, V _{REF}	0	P5	P203	B4	125
GND	-	-	-	GND*	-
I/O	0	-	P204	E6	128
I/O	0	-	-	D5	131
I/O	0	P4	P205	A3	134
I/O	0	-	-	C5	137
I/O	0	P3	P206	B3	140
TCK	-	P2	P207	C4	-
V _{CCO}	0	P1	P208	V _{CCO} Bank 0*	-
V _{CCO}	7	P144	P208	V _{CCO} Bank 7*	-

04/18/01

Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. Pads labelled GND*, V_{CCINT}*, V_{CCO} Bank 0*, V_{CCO} Bank 1*, V_{CCO} Bank 2*, V_{CCO} Bank 3*, V_{CCO} Bank 4*, V_{CCO} Bank 5*, V_{CCO} Bank 6*, V_{CCO} Bank 7* are internally bonded to independent ground or power planes within the package.
3. See "VCCO Banks" for details on V_{CCO} banking.

Additional XC2S50 Package Pins

TQ144

Not Connected Pins					
P104	P105	-	-	-	-

11/02/00

XC2S150 Device Pinouts

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
GND	-	P1	GND*	GND*	-
TMS	-	P2	D3	D3	-
I/O	7	P3	C2	B1	221
I/O	7	-	-	E4	224
I/O	7	-	-	C1	227
I/O	7	-	A2	F5	230
GND	-	-	GND*	GND*	-
I/O	7	P4	B1	D2	233
I/O	7	-	-	E3	236
I/O	7	-	-	F4	239
I/O	7	-	E3	G5	242
I/O	7	P5	D2	F3	245
GND	-	-	GND*	GND*	-
V _{CCO}	7	-	V _{CCO} Bank 7*	V _{CCO} Bank 7*	-
I/O, V _{REF}	7	P6	C1	E2	248
I/O	7	P7	F3	E1	251
I/O	7	-	-	G4	254
I/O	7	-	-	G3	257
I/O	7	-	E2	H5	260
I/O	7	P8	E4	F2	263
I/O	7	-	-	F1	266
I/O, V _{REF}	7	P9	D1	H4	269
I/O	7	P10	E1	G1	272
GND	-	P11	GND*	GND*	-
V _{CCO}	7	P12	V _{CCO} Bank 7*	V _{CCO} Bank 7*	-
V _{CCINT}	-	P13	V _{CCINT} *	V _{CCINT} *	-
I/O	7	P14	F2	H3	275
I/O	7	P15	G3	H2	278
I/O	7	-	-	H1	284
I/O	7	-	F1	J5	287
I/O	7	P16	F4	J2	290
I/O	7	-	-	J3	293
I/O	7	P17	F5	K5	299
I/O	7	P18	G2	K1	302
GND	-	P19	GND*	GND*	-
V _{CCO}	7	-	V _{CCO} Bank 7*	V _{CCO} Bank 7*	-
I/O, V _{REF}	7	P20	H3	K3	305
I/O	7	P21	G4	K4	308
I/O	7	-	H2	L6	311

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	7	P22	G5	L1	314
I/O	7	-	-	L5	317
I/O	7	P23	H4	L4	320
I/O, IRDY ⁽¹⁾	7	P24	G1	L3	323
GND	-	P25	GND*	GND*	-
V _{CCO}	7	P26	V _{CCO} Bank 7*	V _{CCO} Bank 7*	-
V _{CCO}	6	P26	V _{CCO} Bank 6*	V _{CCO} Bank 6*	-
I/O, TRDY ⁽¹⁾	6	P27	J2	M1	326
V _{CCINT}	-	P28	V _{CCINT} *	V _{CCINT} *	-
I/O	6	-	-	M6	332
I/O	6	P29	H1	M3	335
I/O	6	-	J4	M4	338
I/O	6	P30	J1	M5	341
I/O, V _{REF}	6	P31	J3	N2	344
V _{CCO}	6	-	V _{CCO} Bank 6*	V _{CCO} Bank 6*	-
GND	-	P32	GND*	GND*	-
I/O	6	P33	K5	N3	347
I/O	6	P34	K2	N4	350
I/O	6	-	-	N5	356
I/O	6	P35	K1	P2	359
I/O	6	-	K3	P4	362
I/O	6	-	-	R1	365
I/O	6	P36	L1	P3	371
I/O	6	P37	L2	R2	374
V _{CCINT}	-	P38	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	6	P39	V _{CCO} Bank 6*	V _{CCO} Bank 6*	-
GND	-	P40	GND*	GND*	-
I/O	6	P41	K4	T1	377
I/O, V _{REF}	6	P42	M1	R4	380
I/O	6	-	-	T2	383
I/O	6	P43	L4	U1	386
I/O	6	-	M2	R5	389
I/O	6	-	-	V1	392
I/O	6	-	-	T5	395
I/O	6	P44	L3	U2	398
I/O, V _{REF}	6	P45	N1	T3	401
V _{CCO}	6	-	V _{CCO} Bank 6*	V _{CCO} Bank 6*	-
GND	-	-	GND*	GND*	-

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	6	P46	P1	T4	404
I/O	6	-	L5	W1	407
I/O	6	-	-	V2	410
I/O	6	-	-	U4	413
I/O	6	P47	N2	Y1	416
GND	-	-	GND*	GND*	-
I/O	6	-	M4	W2	419
I/O	6	-	-	V3	422
I/O	6	-	-	V4	425
I/O	6	P48	R1	Y2	428
I/O	6	P49	M3	W3	431
M1	-	P50	P2	U5	434
GND	-	P51	GND*	GND*	-
M0	-	P52	N3	AB2	435
V _{CCO}	6	P53	V _{CCO} Bank 6*	V _{CCO} Bank 6*	-
V _{CCO}	5	P53	V _{CCO} Bank 5*	V _{CCO} Bank 5*	-
M2	-	P54	R3	Y4	436
I/O	5	-	-	W5	443
I/O	5	-	-	AB3	446
I/O	5	-	N5	V7	449
GND	-	-	GND*	GND*	-
I/O	5	P57	T2	Y6	452
I/O	5	-	-	AA4	455
I/O	5	-	-	AB4	458
I/O	5	-	P5	W6	461
I/O	5	P58	T3	Y7	464
GND	-	-	GND*	GND*	-
V _{CCO}	5	-	V _{CCO} Bank 5*	V _{CCO} Bank 5*	-
I/O, V _{REF}	5	P59	T4	AA5	467
I/O	5	P60	M6	AB5	470
I/O	5	-	-	V8	473
I/O	5	-	-	AA6	476
I/O	5	-	T5	AB6	479
I/O	5	P61	N6	AA7	482
I/O	5	-	-	W7	485
I/O, V _{REF}	5	P62	R5	W8	488
I/O	5	P63	P6	Y8	491
GND	-	P64	GND*	GND*	-

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
V _{CCO}	5	P65	V _{CCO} Bank 5*	V _{CCO} Bank 5*	-
V _{CCINT}	-	P66	V _{CCINT} *	V _{CCINT} *	-
I/O	5	P67	R6	AA8	494
I/O	5	P68	M7	V9	497
I/O	5	-	-	W9	503
I/O	5	-	-	AB9	506
I/O	5	P69	N7	Y9	509
I/O	5	-	-	V10	512
I/O	5	P70	T6	W10	518
I/O	5	P71	P7	AB10	521
GND	-	P72	GND*	GND*	-
V _{CCO}	5	-	V _{CCO} Bank 5*	V _{CCO} Bank 5*	-
I/O, V _{REF}	5	P73	P8	Y10	524
I/O	5	P74	R7	V11	527
I/O	5	-	T7	W11	530
I/O	5	P75	T8	AB11	533
I/O	5	-	-	U11	536
V _{CCINT}	-	P76	V _{CCINT} *	V _{CCINT} *	-
I, GCK1	5	P77	R8	Y11	545
V _{CCO}	5	P78	V _{CCO} Bank 5*	V _{CCO} Bank 5*	-
V _{CCO}	4	P78	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
GND	-	P79	GND*	GND*	-
I, GCK0	4	P80	N8	W12	546
I/O	4	P81	N9	U12	550
I/O	4	-	-	V12	553
I/O	4	P82	R9	Y12	556
I/O	4	-	N10	AA12	559
I/O	4	P83	T9	AB13	562
I/O, V _{REF}	4	P84	P9	AA13	565
V _{CCO}	4	-	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
GND	-	P85	GND*	GND*	-
I/O	4	P86	M10	Y13	568
I/O	4	P87	R10	V13	571
I/O	4	-	-	W14	577
I/O	4	P88	P10	AA14	580
I/O	4	-	-	V14	583
I/O	4	-	-	Y14	586
I/O	4	P89	T10	AB15	592

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O, IRDY ⁽¹⁾	2	P132	H16	L20	767
I/O	2	P133	H14	L17	770
I/O	2	-	-	L18	773
I/O	2	P134	H15	L21	776
I/O	2	-	J13	L22	779
I/O (D3)	2	P135	G16	K20	782
I/O, V _{REF}	2	P136	H13	K21	785
V _{CCO}	2	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P137	GND*	GND*	-
I/O	2	P138	G14	K22	788
I/O	2	P139	G15	J21	791
I/O	2	-	-	J20	797
I/O	2	P140	G12	J18	800
I/O	2	-	F16	J22	803
I/O	2	-	-	J19	806
I/O	2	P141	G13	H19	812
I/O (D2)	2	P142	F15	H20	815
V _{CCINT}	-	P143	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	2	P144	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	P145	GND*	GND*	-
I/O (D1)	2	P146	E16	H22	818
I/O, V _{REF}	2	P147	F14	H18	821
I/O	2	-	-	G21	824
I/O	2	P148	D16	G18	827
I/O	2	-	F12	G20	830
I/O	2	-	-	G19	833
I/O	2	-	-	F22	836
I/O	2	P149	E15	F19	839
I/O, V _{REF}	2	P150	F13	F21	842
V _{CCO}	2	-	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
GND	-	-	GND*	GND*	-
I/O	2	P151	E14	F20	845
I/O	2	-	C16	F18	848
I/O	2	-	-	E22	851
I/O	2	-	-	E21	854
I/O	2	P152	E13	D22	857
GND	-	-	GND*	GND*	-
I/O	2	-	B16	E20	860
I/O	2	-	-	D21	863

XC2S150 Device Pinouts (Continued)

XC2S150 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	2	-	-	C22	866
I/O (DIN, D0)	2	P153	D14	D20	869
I/O (DOUT, BUSY)	2	P154	C15	C21	872
CCLK	2	P155	D15	B22	875
V _{CCO}	2	P156	V _{CCO} Bank 2*	V _{CCO} Bank 2*	-
V _{CCO}	1	P156	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
TDO	2	P157	B14	A21	-
GND	-	P158	GND*	GND*	-
TDI	-	P159	A15	B20	-
I/O ($\overline{\text{CS}}$)	1	P160	B13	C19	0
I/O ($\overline{\text{WRITE}}$)	1	P161	C13	A20	3
I/O	1	-	-	B19	6
I/O	1	-	-	C18	9
I/O	1	-	C12	D17	12
GND	-	-	GND*	GND*	-
I/O	1	P162	A14	A19	15
I/O	1	-	-	B18	18
I/O	1	-	-	E16	21
I/O	1	-	D12	C17	24
I/O	1	P163	B12	D16	27
GND	-	-	GND*	GND*	-
V _{CCO}	1	-	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
I/O, V _{REF}	1	P164	C11	A18	30
I/O	1	P165	A13	B17	33
I/O	1	-	-	E15	36
I/O	1	-	-	A17	39
I/O	1	-	D11	D15	42
I/O	1	P166	A12	C16	45
I/O	1	-	-	D14	48
I/O, V _{REF}	1	P167	E11	E14	51
I/O	1	P168	B11	A16	54
GND	-	P169	GND*	GND*	-
V _{CCO}	1	P170	V _{CCO} Bank 1*	V _{CCO} Bank 1*	-
V _{CCINT}	-	P171	V _{CCINT} *	V _{CCINT} *	-
I/O	1	P172	A11	C15	57
I/O	1	P173	C10	B15	60
I/O	1	-	-	A15	66
I/O	1	-	-	F12	69

Additional XC2S150 Package Pins

PQ208

Not Connected Pins					
P55	P56	-	-	-	-

11/02/00

FG256

V _{CCINT} Pins					
C3	C14	D4	D13	E5	E12
M5	M12	N4	N13	P3	P14
V _{CCO} Bank 0 Pins					
E8	F8	-	-	-	-
V _{CCO} Bank 1 Pins					
E9	F9	-	-	-	-
V _{CCO} Bank 2 Pins					
H11	H12	-	-	-	-
V _{CCO} Bank 3 Pins					
J11	J12	-	-	-	-
V _{CCO} Bank 4 Pins					
L9	M9	-	-	-	-
V _{CCO} Bank 5 Pins					
L8	M8	-	-	-	-
V _{CCO} Bank 6 Pins					
J5	J6	-	-	-	-
V _{CCO} Bank 7 Pins					
H5	H6	-	-	-	-
GND Pins					
A1	A16	B2	B15	F6	F7
F10	F11	G6	G7	G8	G9
G10	G11	H7	H8	H9	H10
J7	J8	J9	J10	K6	K7
K8	K9	K10	K11	L6	L7
L10	L11	R2	R15	T1	T16
Not Connected Pins					
P4	R4	-	-	-	-

11/02/00

Additional XC2S150 Package Pins (Continued)

FG456

V _{CCINT} Pins					
E5	E18	F6	F17	G7	G8
G9	G14	G15	G16	H7	H16
J7	J16	P7	P16	R7	R16
T7	T8	T9	T14	T15	T16
U6	U17	V5	V18	-	-
V _{CCO} Bank 0 Pins					
F7	F8	F9	F10	G10	G11
V _{CCO} Bank 1 Pins					
F13	F14	F15	F16	G12	G13
V _{CCO} Bank 2 Pins					
G17	H17	J17	K16	K17	L16
V _{CCO} Bank 3 Pins					
M16	N16	N17	P17	R17	T17
V _{CCO} Bank 4 Pins					
T12	T13	U13	U14	U15	U16
V _{CCO} Bank 5 Pins					
T10	T11	U7	U8	U9	U10
V _{CCO} Bank 6 Pins					
M7	N6	N7	P6	R6	T6
V _{CCO} Bank 7 Pins					
G6	H6	J6	K6	K7	L7
GND Pins					
A1	A22	B2	B21	C3	C20
J9	J10	J11	J12	J13	J14
K9	K10	K11	K12	K13	K14
L9	L10	L11	L12	L13	L14
M9	M10	M11	M12	M13	M14
N9	N10	N11	N12	N13	N14
P9	P10	P11	P12	P13	P14
Y3	Y20	AA2	AA21	AB1	AB22
Not Connected Pins					
A2	A6	A12	A13	A14	B11
B16	C2	C8	C9	D1	D4
D18	D19	E13	E17	E19	F11
G2	G22	H21	J1	J4	K2
K18	K19	L2	L19	M2	M17
M21	N1	P1	P5	P22	R3
R20	R22	U3	U18	V6	W4
W13	W15	W19	Y5	Y22	AA1
AA3	AA9	AA10	AA11	AA16	AB7
AB8	AB12	AB14	AB21	-	-

11/02/00

XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I, GCK0	4	P80	N8	W12	636
I/O	4	P81	N9	U12	640
I/O	4	-	-	V12	646
I/O	4	P82	R9	Y12	649
I/O	4	-	N10	AA12	652
I/O	4	-	-	W13	655
I/O	4	P83	T9	AB13	661
I/O, V _{REF}	4	P84	P9	AA13	664
V _{CCO}	4	-	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
GND	-	P85	GND*	GND*	-
I/O	4	P86	M10	Y13	667
I/O	4	P87	R10	V13	670
I/O	4	-	-	AB14	673
I/O	4	-	-	W14	676
I/O	4	P88	P10	AA14	679
GND	-	-	GND*	GND*	-
I/O	4	-	-	V14	682
I/O	4	-	-	Y14	685
I/O	4	-	-	W15	688
I/O	4	P89	T10	AB15	691
I/O	4	P90	R11	AA15	694
V _{CCINT}	-	P91	V _{CCINT} *	V _{CCINT} *	-
V _{CCO}	4	P92	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
GND	-	P93	GND*	GND*	-
I/O	4	P94	M11	Y15	697
I/O, V _{REF}	4	P95	T11	AB16	700
I/O	4	-	-	AB17	706
I/O	4	P96	N11	V15	709
GND	-	-	GND*	GND*	-
I/O	4	-	R12	Y16	712
I/O	4	-	-	AA17	715
I/O	4	-	-	W16	718
I/O	4	P97	P11	AB18	721
I/O, V _{REF}	4	P98	T12	AB19	724
V _{CCO}	4	-	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
GND	-	-	GND*	GND*	-
I/O	4	P99	T13	Y17	727
I/O	4	-	N12	V16	730
I/O	4	-	-	AA18	733

XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
I/O	4	-	-	W17	739
I/O, V _{REF}	4	P100	R13	AB20	742
GND	-	-	GND*	GND*	-
I/O	4	-	P12	AA19	745
I/O	4	-	-	V17	748
I/O	4	-	-	Y18	751
I/O	4	P101	P13	AA20	757
I/O	4	P102	T14	W18	760
GND	-	P103	GND*	GND*	-
DONE	3	P104	R14	Y19	763
V _{CCO}	4	P105	V _{CCO} Bank 4*	V _{CCO} Bank 4*	-
V _{CCO}	3	P105	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
PROGRAM	-	P106	P15	W20	766
I/O (INIT)	3	P107	N15	V19	767
I/O (D7)	3	P108	N14	Y21	770
I/O	3	-	-	V20	776
I/O	3	-	-	AA22	779
I/O	3	-	T15	W21	782
GND	-	-	GND*	GND*	-
I/O, V _{REF}	3	P109	M13	U20	785
I/O	3	-	-	U19	788
I/O	3	-	-	V21	794
GND	-	-	GND*	GND*	-
I/O	3	-	R16	T18	797
I/O	3	P110	M14	W22	800
GND	-	-	GND*	GND*	-
V _{CCO}	3	-	V _{CCO} Bank 3*	V _{CCO} Bank 3*	-
I/O, V _{REF}	3	P111	L14	U21	803
I/O	3	P112	M15	T20	806
I/O	3	-	-	T19	809
I/O	3	-	-	V22	812
I/O	3	-	L12	T21	815
GND	-	-	GND*	GND*	-
I/O	3	P113	P16	R18	818
I/O	3	-	-	U22	821
I/O, V _{REF}	3	P114	L13	R19	827
I/O (D6)	3	P115	N16	T22	830
GND	-	P116	GND*	GND*	-

XC2S200 Device Pinouts (Continued)

XC2S200 Pad Name		PQ208	FG256	FG456	Bndry Scan
Function	Bank				
GND	-	P198	GND*	GND*	-
I/O	0	P199	A5	B7	188
I/O, V _{REF}	0	P200	C6	E8	191
I/O	0	-	-	D8	197
I/O	0	P201	B5	C7	200
GND	-	-	GND*	GND*	-
I/O	0	-	D6	D7	203
I/O	0	-	-	B6	206
I/O	0	-	-	A5	209
I/O	0	P202	A4	D6	212
I/O, V _{REF}	0	P203	B4	C6	215
V _{CCO}	0	-	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
GND	-	-	GND*	GND*	-
I/O	0	P204	E6	B5	218
I/O	0	-	D5	E7	221
I/O	0	-	-	A4	224
I/O	0	-	-	E6	230
I/O, V _{REF}	0	P205	A3	B4	233
GND	-	-	GND*	GND*	-
I/O	0	-	C5	A3	236
I/O	0	-	-	B3	239
I/O	0	-	-	D5	242
I/O	0	P206	B3	C5	248
TCK	-	P207	C4	C4	-
V _{CCO}	0	P208	V _{CCO} Bank 0*	V _{CCO} Bank 0*	-
V _{CCO}	7	P208	V _{CCO} Bank 7*	V _{CCO} Bank 7*	-

04/18/01

Notes:

1. IRDY and TRDY can only be accessed when using Xilinx PCI cores.
2. Pads labelled GND*, V_{CCINT}*, V_{CCO} Bank 0*, V_{CCO} Bank 1*, V_{CCO} Bank 2*, V_{CCO} Bank 3*, V_{CCO} Bank 4*, V_{CCO} Bank 5*, V_{CCO} Bank 6*, V_{CCO} Bank 7* are internally bonded to independent ground or power planes within the package.
3. See "VCCO Banks" for details on V_{CCO} banking.

Additional XC2S200 Package Pins

PQ208

Not Connected Pins					
P55	P56	-	-	-	-

11/02/00

FG256

V _{CCINT} Pins					
C3	C14	D4	D13	E5	E12
M5	M12	N4	N13	P3	P14
V _{CCO} Bank 0 Pins					
E8	F8	-	-	-	-
V _{CCO} Bank 1 Pins					
E9	F9	-	-	-	-
V _{CCO} Bank 2 Pins					
H11	H12	-	-	-	-
V _{CCO} Bank 3 Pins					
J11	J12	-	-	-	-
V _{CCO} Bank 4 Pins					
L9	M9	-	-	-	-
V _{CCO} Bank 5 Pins					
L8	M8	-	-	-	-
V _{CCO} Bank 6 Pins					
J5	J6	-	-	-	-
V _{CCO} Bank 7 Pins					
H5	H6	-	-	-	-
GND Pins					
A1	A16	B2	B15	F6	F7
F10	F11	G6	G7	G8	G9
G10	G11	H7	H8	H9	H10
J7	J8	J9	J10	K6	K7
K8	K9	K10	K11	L6	L7
L10	L11	R2	R15	T1	T16
Not Connected Pins					
P4	R4	-	-	-	-

Additional XC2S200 Package Pins (Continued)

11/02/00

FG456

V _{CCINT} Pins					
E5	E18	F6	F17	G7	G8
G9	G14	G15	G16	H7	H16
J7	J16	P7	P16	R7	R16
T7	T8	T9	T14	T15	T16
U6	U17	V5	V18	-	-
V _{CCO} Bank 0 Pins					
F7	F8	F9	F10	G10	G11
V _{CCO} Bank 1 Pins					
F13	F14	F15	F16	G12	G13
V _{CCO} Bank 2 Pins					
G17	H17	J17	K16	K17	L16
V _{CCO} Bank 3 Pins					
M16	N16	N17	P17	R17	T17
V _{CCO} Bank 4 Pins					
T12	T13	U13	U14	U15	U16
V _{CCO} Bank 5 Pins					
T10	T11	U7	U8	U9	U10
V _{CCO} Bank 6 Pins					
M7	N6	N7	P6	R6	T6
V _{CCO} Bank 7 Pins					

Additional XC2S200 Package Pins (Continued)

G6	H6	J6	K6	K7	L7
GND Pins					
A1	A22	B2	B21	C3	C20
J9	J10	J11	J12	J13	J14
K9	K10	K11	K12	K13	K14
L9	L10	L11	L12	L13	L14
M9	M10	M11	M12	M13	M14
N9	N10	N11	N12	N13	N14
P9	P10	P11	P12	P13	P14
Y3	Y20	AA2	AA21	AB1	AB22
Not Connected Pins					
A2	A6	A12	B11	B16	C2
D1	D4	D18	D19	E17	E19
G2	G22	L2	L19	M2	M21
R3	R20	U3	U18	V6	W4
W19	Y5	Y22	AA1	AA3	AA11
AA16	AB7	AB12	AB21	-	-

11/02/00

Revision History

Version No.	Date	Description
2.0	09/18/00	Sectioned the Spartan-II Family data sheet into four modules. Corrected all known errors in the pinout tables.
2.1	10/04/00	Added notes requiring $\overline{\text{PWDN}}$ to be tied to V _{CCINT} when unused.
2.2	11/02/00	Removed the Power Down feature.
2.3	03/05/01	Added notes on pinout tables for IRDY and TRDY.
2.4	04/30/01	Reinstated XC2S50 V _{CCO} Bank 7, GND, and "not connected" pins missing in version 2.3.
2.5	09/03/03	Added caution about Not Connected Pins to XC2S30 pinout tables on page 76 .
2.8	06/13/08	Added " Package Overview " section. Added notes to clarify shared V _{CCO} banks. Updated description and links. Updated all modules for continuous page, figure, and table numbering. Synchronized all modules to v2.8.